

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/806,724	CHANG ET AL.	
Examiner	Art Unit	_
Thomas R. Peeso	2132	

SEARCHED				
Class	Subclass	Date	Examiner	
713	201	3MA/a	- +P	
	160		.,	
	168	3MA/as		
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	172			
	185			
				

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
713	201	OBMAYO	- f		
	160				
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	170				
	172				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
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